

FFR 27 2006

FORM PTO-146 PATENT TRADE OFFICE		Docket No.: I431.144.101/FIN 503 PCT/US	Serial No.: 10/564,650
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		Applicant: Klaus Dworski et al.	
		Filing Date: January 13, 2006	Group Art: Unknown

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/MN/ AA	2002/0105353	08/2002	Mori et al.	-----	-----	
AB	3,852,123	12/1974	Goltz	-----	-----	
AC	4,746,902	05/1988	Tol et al.	-----	-----	
/MN/ AD	6,127,869	10/2000	Hirasaka	-----	-----	
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FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translated Yes No
/MN/ AM		0 550 187	07/1993	EPO	-----	-----	Yes
	AN						Yes
	AO						Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/MN/ AP	A.K. Lu, G.W. Roberts, "An Analog Multi-Tone Signal Generator for Built-In Self-Test Applications", ITC 1994 Proceedings, Baltimore, USA Paper 27.3, pp. 650-659.	
AQ	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", ISCAS 1993 Proceedings, Chicago, May 1993, pp. 1298-1301.	
AR	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", IEEE Trans. On Circuits and Systems - II: Analog and Digital Signal Processing, Vol. 41, No. 7, July 1994.	
AS	M. Hafed, G. Roberts, "Test and Evaluation of Multiple Embedded Mixed-Signal Test Cores", ITC 2002 Proceedings, Baltimore, USA, Paper 35.3, pp. 1022-1030.	
AT	T.A. Rebeld, F.H. Irons: "A phase-plane approach to the compensation of high-speed analog-to-digital converters" IEEE International Symposium on Circuits and Systems XP 008036387 . 1987 .	
/MN/ AU	Hofner T.C.: "INL/DNL Measurements for High-Speed ADCS" XP000947286 . 12-1999 .	

EXAMINER: /Michael Nghiem/ DATE CONSIDERED: 05/20/2009

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.